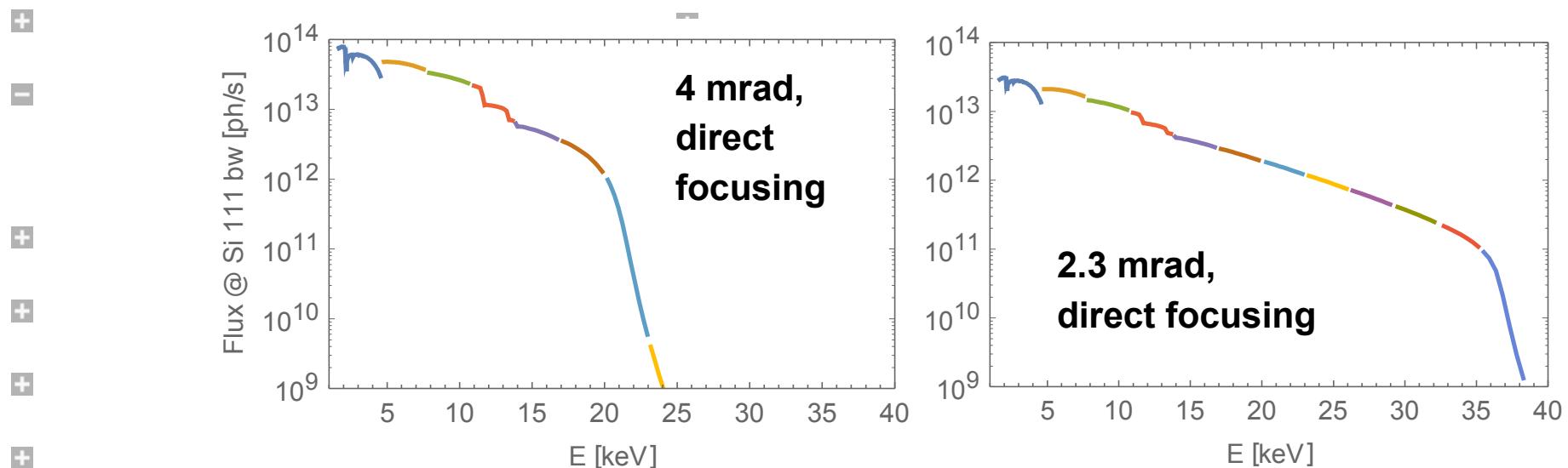
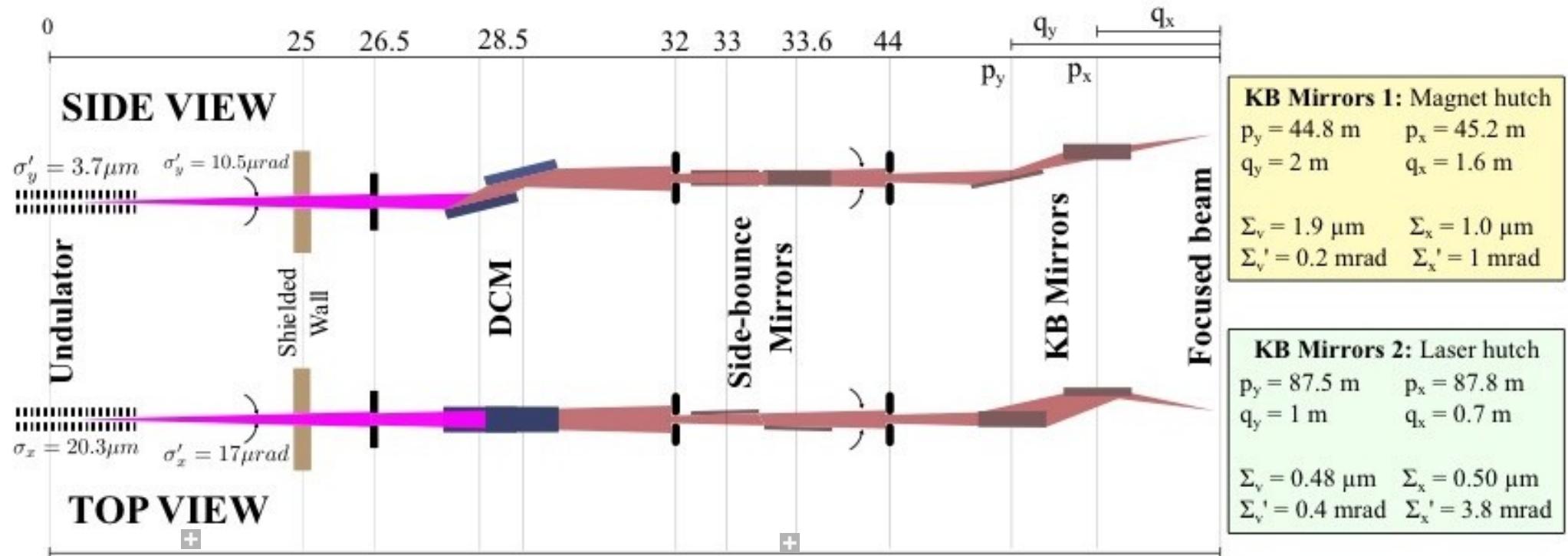


EMA beamline at Sirius: Extreme condition x-ray Methods of Analysis

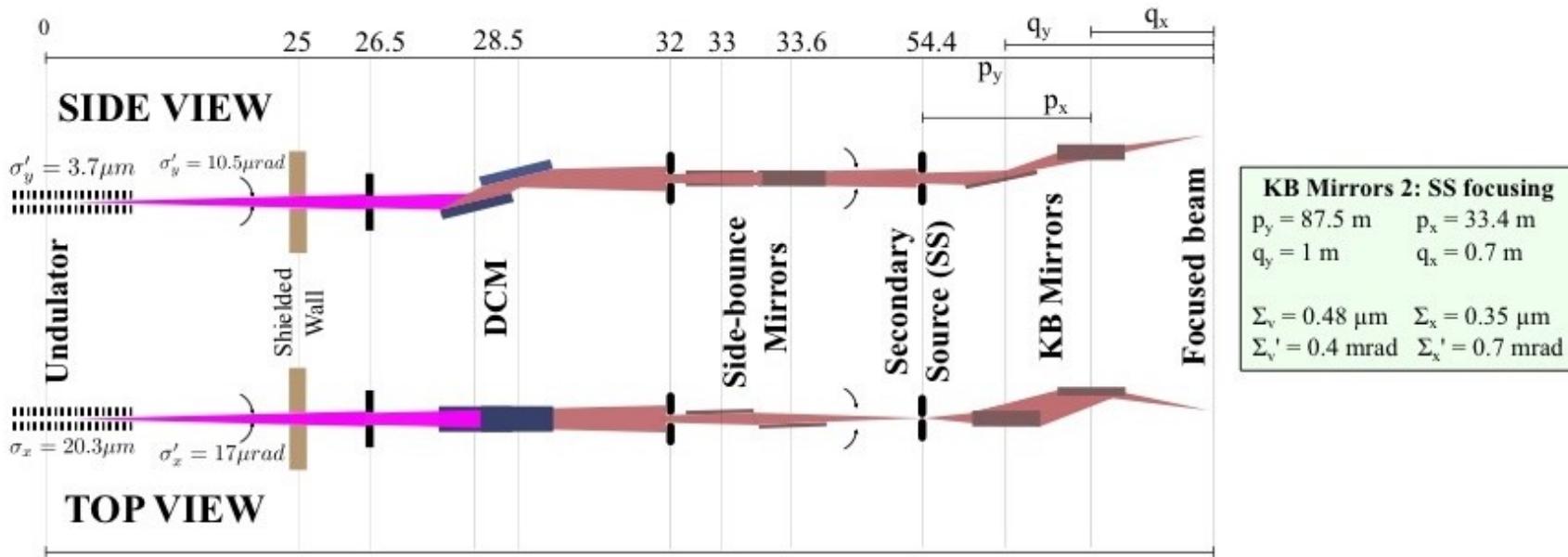
**N. M. Souza-Neto*, F. A. Lima, A. M. G.
Carvalho, F. C. B. Maia, A. M. Espindola, J.
Fonseca Jr, M. A. S. Eleoterio**

***narcizo.souza@lnls.br**

Direct focusing scheme



Secondary source focusing



- If the experiment needs round divergence
- Over illumination improves stability
- There is a compromise in flux (a factor of 10 at least)

KB + Secondary source	Horiz. (Bender)	Vert. (Bender)			
Slope error (μrad):	0.1	0.1			
Length (m):	0.3	0.3			
Source to mirror (m):	33.4	87.5			
Angle (mrad):	4	4			
acceptance (μm):	1200.0	1200.0			
acceptance (#of σ):	2.00	1.52			
beam intensity acceptance:	0.683	0.553			
Size and divergence (FWHM):					
Units:	Σ_x μm	Σ_x' μrad	Σ_y μm	Σ_y' μrad	
Vert. Mirror (m):	87.5	3685	49.4	1855	24.8
Hor. Mirror (m):	33.4	1410	49.4	714	24.8
focal position (m):	88.2 88.5 90 95 97 100	0.20 0.35 1.1 3.6 4.5 6.0	1252 716 228 70 54 41	0.34 0.48 1.2 3.6 4.6 6.0	646 452 181 60 48 36